

Subclass	
Class	
ISSUE CLASSIFICATION	

PATENT NUMBER

## U.S. UTILITY Patent Application

O.I.P.E.

PATENT DATE

mH  
SCANNED Ed. 3 on TM

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/887791		216	062	1765	Ahmed

APPLICANTS

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P.G.P. 1/2  
done

Focused ion beam process for removal of copper

TITLE

PTO-2040  
12/99

## SEARCHING CLASSIFICATION

## CROSS REFERENCE

 Continued on page 2 of this file jacket

TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
NOTICE OF ALLOWANCE MAILED					
(Assistant Examiner) (Date)					
(Primary Examiner) (Date)					
(Legal Instruments Examiner) (Date)					
ISSUE FEE					
			Amount Due	Date Paid	
ISSUE BATCH NUMBER					

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